



Docket No.: N9460.0020/P020  
(PATENT)

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

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In re Patent Application of:  
Eiko Nakazawa et al.

Application No.: 10/720,251

Confirmation No.: 3656

Filed: November 25, 2003

Art Unit: 2881

For: SAMPLE OBSERVATION METHOD AND  
TRANSMISSION ELECTRON MICROSCOPE

Examiner: A. G. Quash

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**COMMENTS ON EXAMINER'S  
STATEMENT OF REASONS FOR ALLOWANCE**

U.S. Patent and Trademark Office  
Customer Window, Mail Stop Issue Fee  
Randolph Building  
401 Dulany Street  
Alexandria, VA 22314

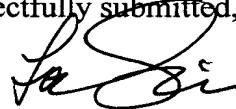
Dear Sir:

The Examiner's statement of reasons for allowance, attached to the Notice of Allowance, refers to limitations that do not appear in the allowed claims. The Examiner's statement is not co-extensive with the actual language of the claims. For example, independent claim 6 does not recited the limitation of "computing a correlation between the specified object image and the a stored object image and a stored reference image and displaying the result of

computation for different tilt angles.” There are also other areas in which the Examiner’s statements diverges from the actual language of the allowed claims. The scope of the allowed claims should be determined by the actual language thereof.

Dated: September 9, 2005

Respectfully submitted,

 28,371  
for

By \_\_\_\_\_

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